

FAST 74F1764/1765 74F1764-1/1765-1 1 Megabit DRAM Dual-Ported Controller

FEATURES

- Allows two microprocessors to access the same bank of dynamic RAM
- Performs arbitration, signal timing, address multiplexing and refresh
- 10 address output pins allow direct control of up to 1Mbit dynamic RAMs
- External address multiplexing enables control of 4Mbit (or greater) dynamic RAMs
- Separate refresh clock allows adjustable refresh timing
- 74F1764/1765-1 have on-chip 20-bit address input latch
- Allows control of dynamic RAMS with row access times down to 40ns
- 74F1764/1765 output drivers designed for incident wave switching
- 74F1764-1/1765-1 output drivers designed for first reflected wave switching

DESCRIPTION

The 74F1764/1765 DRAM Dual-ported Controller is a high speed synchronous dual-port arbiter and timing generator that allows two microprocessors, microcontrollers, or any other memory accessing device to share the same block of DRAM. The device performs arbitration, signal timing, address multiplexing, and refresh address generation, replacing up to 25 discrete devices.

74F1764 vs 74F1765

The 74F1764 though functionally and pin to pin compatible with the 74F1765 differs from the later in that it has an on-chip address input latch. This is useful in systems that have unlatched or multiplexed address and data bus.

Product Specification

TYPE	TYPICAL f_{MAX}	TYPICAL SUPPLY CURRENT (TOTAL)
74F1764/1765	150MHz	150mA
74F1764-1/1765-1	150MHz	125mA

ORDERING INFORMATION

PACKAGES	COMMERCIAL RANGE $V_{CC} = 5V \pm 10\%$; $T_A = 0^\circ C$ to $+70^\circ C$
48-Pin Plastic DIP	N74F1764N, N74F1765N, N74F1764-1N, N74F1765-1N
44-Pin PLCC	N74F1764A, N74F1765A, N74F1764-1A, N74F1765-1A

INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

PINS	DESCRIPTION	74F(U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
$RA_0 - RA_9$	Row address inputs	1.0/1.0	20 μ A/0.6mA
$CA_0 - CA_9$	Column address inputs	1.0/1.0	20 μ A/0.6mA
REQ_1, REQ_2	Memory access request inputs	1.0/1.0	20 μ A/0.6mA
CP	Clock input	1.0/1.0	20 μ A/0.6mA
RCP	Refresh clock input	1.0/1.0	20 μ A/0.6mA
SEL_1, SEL_2	Select outputs	F1764/1765	750/40 15.0mA/24mA
		F1764-1/1765-1	1000/13.3 20.0mA/8mA
$MA_0 - MA_9$	Memory address outputs	F1764/1765	750/40 15.0mA/24mA
		F1764-1/1765-1	1000/13.3 20.0mA/8mA
GNT	Grant output	F1764/1765	750/40 15.0mA/24mA
		F1764-1/1765-1	1000/13.3 20.0mA/8mA
RAS	Row address strobe output	F1764/1765	750/40 15.0mA/24mA
		F1764-1/1765-1	1000/13.3 20.0mA/8mA
WG	Write gate output	F1764/1765	750/40 15.0mA/24mA
		F1764-1/1765-1	1000/13.3 20.0mA/8mA
CASEN	Column address strobe enable output	F1764/1765	750/40 15.0mA/24mA
		F1764-1/1765-1	1000/13.3 20.0mA/8mA
DTACK	Data transfer acknowledge output	F1764/1765	750/40 15.0mA/24mA
		F1764-1/1765-1	1000/13.3 20.0mA/8mA

NOTE:

1. One (1.0) FAST Unit Load is defined as: 20 μ A in the High state and 0.6mA in the Low state

1 Megabit DRAM Dual-Ported Controllers

FAST 74F1764, 74F1765,
74F1764-1, 74F1765-1**DC ELECTRICAL CHARACTERISTICS** (Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER		TEST CONDITIONS ¹			LIMITS			UNIT
						Min	Typ ²	Max	
V _{OH}	High-level output voltage	74F1764 74F1765	V _{CC} = MIN, V _{IL} = MAX, V _{IH} = MIN	I _{OH} = -15mA	±10%V _{CC}	2.5			V
V _{OH2} ³				I _{OH2} ³ = -35mA	±5%V _{CC}	2.7			V
V _{OH}		74F1764-1 74F1765-1	V _{CC} = MIN, V _{IL} = MAX, V _{IH} = MIN	I _{OH} = -20mA	±10%V _{CC}	2.4	2.7		V
					±5%V _{CC}	2.6	3.0		V
V _{OL}	Low-level output voltage	74F1764 74F1765	V _{CC} = MIN, V _{IL} = MAX, V _{IH} = MIN	I _{OL} = 24mA	±10%V _{CC}		0.35	0.50	V
V _{OL2} ³				I _{OL2} ⁴ = 60mA	±5%V _{CC}		0.35	0.50	V
V _{OL}		74F1764-1 74F1765-1	V _{CC} = MIN, V _{IL} = MAX, V _{IH} = MIN	I _{OL} = 8mA	±10%V _{CC}		0.45	0.80	V
					±5%V _{CC}		0.30	0.50	V
V _{OL2} ³		74F1764-1 74F1765-1	V _{CC} = MIN, V _{IL} = MAX, V _{IH} = MIN	I _{OL2} ³ = 75mA	±10%V _{CC}		0.30	0.50	V
					±5%V _{CC}		2.1	2.5	V
V _{IK}	Input clamp voltage		V _{CC} = MIN, I _I = I _{IK}				-0.73	-1.2	V
I _I	Input current at maximum input voltage		V _{CC} = 0.0V, V _I = 7.0V					100	μA
I _{IH}	High-level input current		V _{CC} = MAX, V _I = 2.7V					20	μA
I _{IL}	Low-level input current		V _{CC} = MAX, V _I = 0.5V					-0.6	mA
I _{OS}	Short-circuit output current ⁵		74F1764 74F1765	V _{CC} = MAX		-100		-225	mA
			74F1764-1 74F1765-1	V _{CC} = MAX		-60	100	-150	mA
I _{CC}	Supply current (total)	I _{CCH}	74F1764 74F1765	V _{CC} = MAX			150	200	mA
		I _{CCL}				165	210	mA	
		I _{CCH}	74F1764-1 74F1765-1				120	165	mA
		I _{CCL}				125	170	mA	

NOTES:

1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.

2. All typical values are at $V_{CC} = 5\text{V}$, $T_A = 25^\circ\text{C}$.

3. Refer to Appendix A.

4. Refer to Appendix A.

5. Not more than one output should be shorted at a time. For testing I_{OS} , the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.